


<b>Search Notes</b>  	<b>Application/Control No.</b>  10565709	<b>Applicant(s)/Patent Under Reexamination</b>  ABEDI, SAIED
	<b>Examiner</b>  Meless N Zewdu	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
370	230-235, 237-238, 328-333, 338, 341-350, 395.42, 431-432, 443-444, 455	5/15/08	M.Z.
455	132-135, 428, 432.3, 445, 448-451, 452.1-452.2, 453, 466, 509, 512-517, 524-525, 550.1, 561	5/15/08	M.Z.

SEARCH NOTES		
Search Notes	Date	Examiner
Searched: US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT & IBM_TDB	5/15/08	M.Z.
Searched by: text, class-subclass; assignee and inventor (see attached search history)	5/15/08	M.Z.
Search has been updated.	1/9/09	M.Z.
Search has been updated.	12/20/2009	M.Z.
Search has been updated.	6/17/2010	M.Z.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Meless N Zewdu/ Primary Examiner.Art Unit 2617
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